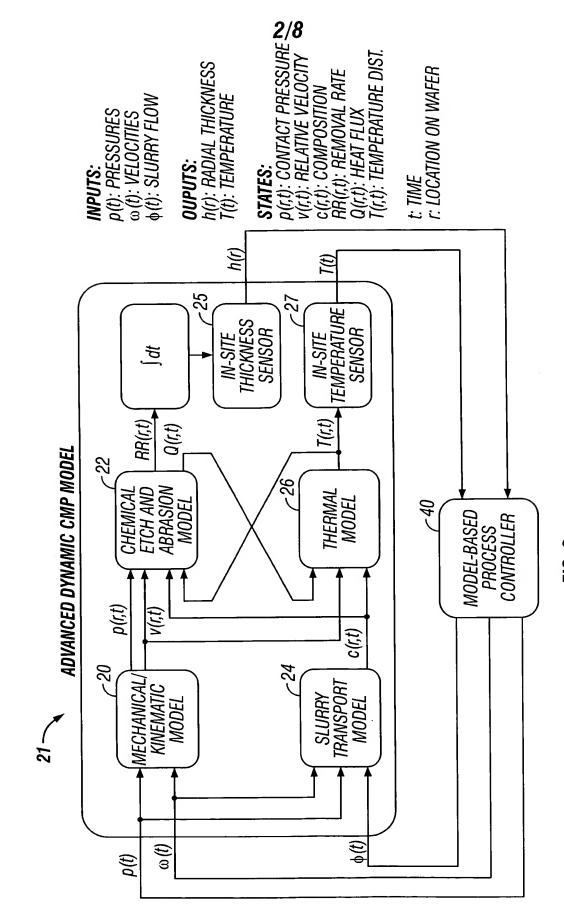


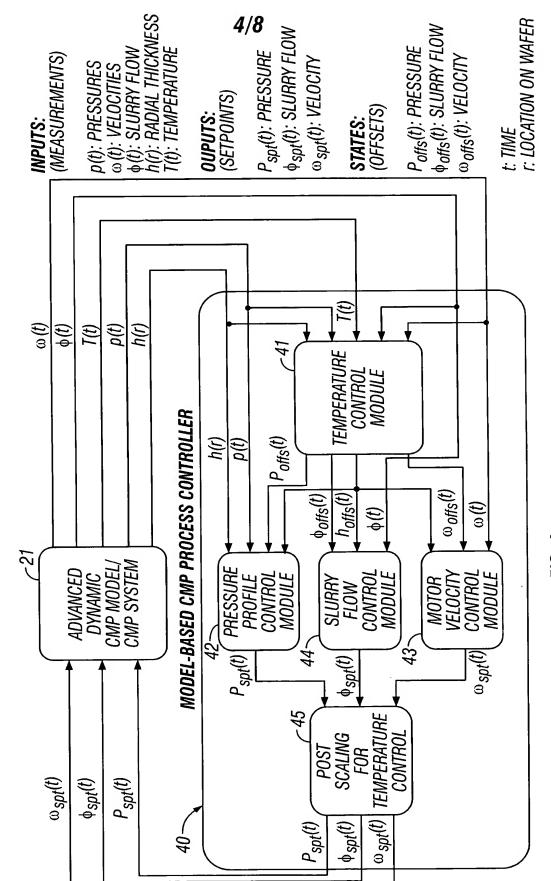
FIG. 1 (Prior Art)



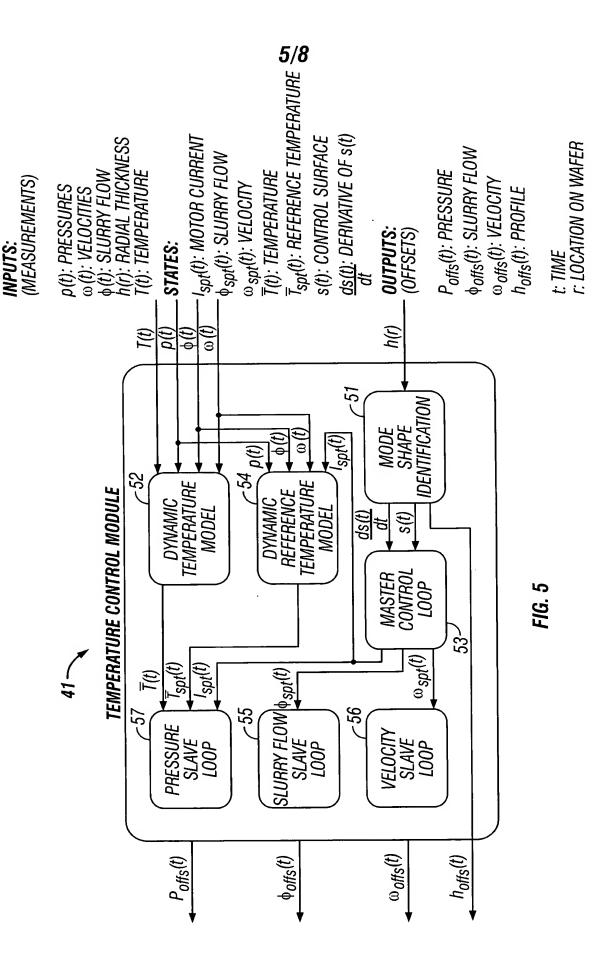
ò

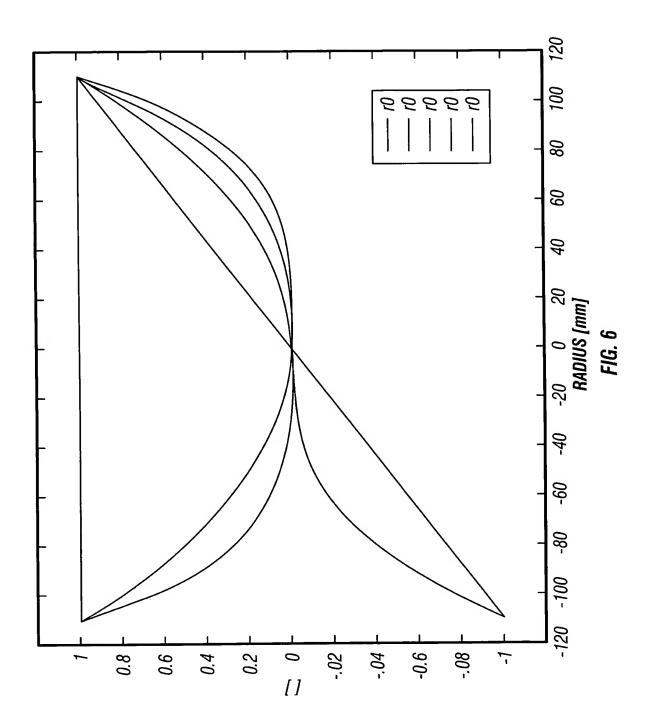
FIG. 2

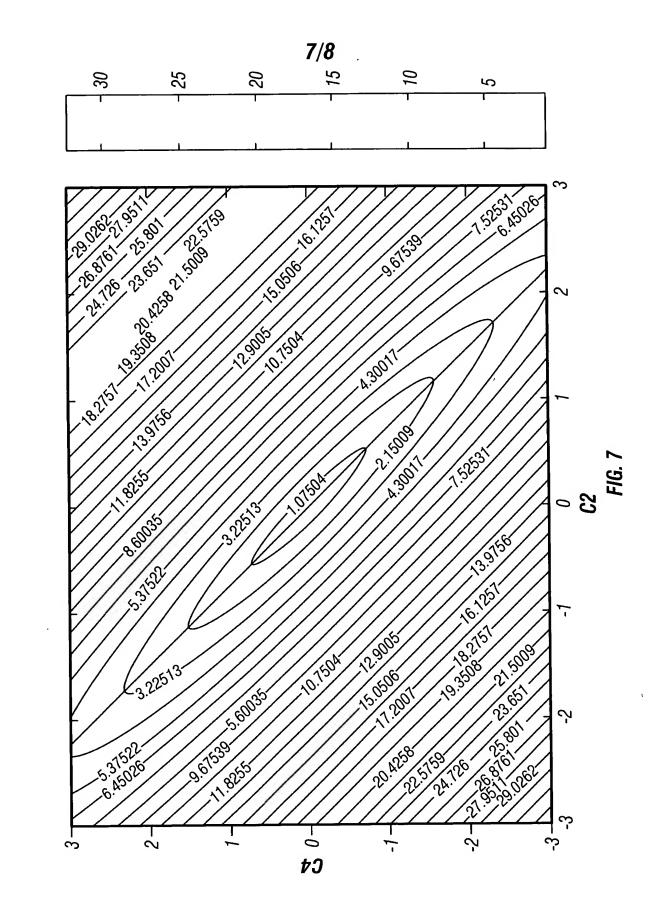
FIG. 3



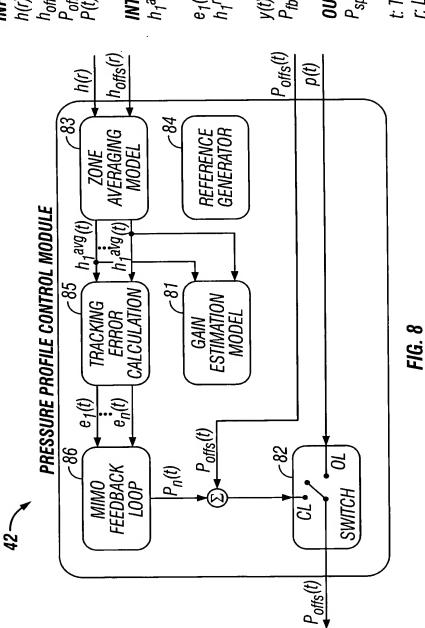
F/G. 4







• •



INPUTS:

h(r): RADIAL THICKNESS h_{offs}(r): FEED FORWARD PROFILE P_{offs}(t): OFFSET PRESSURES P(t): PRESSURES

INTERNAL SIGNALS:

 $h_1^{avg}(t)..h_n^{avg}(t)$: ZONE AVERAGE THICKNESS $e_1(t)..e_n(t)$: TRACKING ERROR $h_1^{ref}(t)$: ZONE REFERENCE

THICKNESS y(t): GAIN ESTIMATION P_{tb}(t): FEEDBACK PRESSURES

OUTPUTS:

P_{spt}(t): SETPOINT PRESSURES

t: TIME

r: Location on Wafer